Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/660,517	CHANG, SHU-MEI		
Examiner	Art Unit		
Alan S. Chen	2182		

	SEARCHED					
Class	Subclass	Date	Examiner			
710	12	4/28/2005	ASC			
1	18					
	19					
	63					
	64					
	72	4				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	4/28/2005	ASC		
see search literary pa	09/20185	Asc		
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